



EMI TEST REPORT

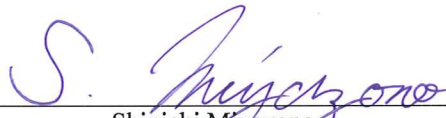
Test Report No. : 10775427H-B

Applicant : Sharp Corporation, Communication Systems Division.
Type of Equipment : Smart Phone
Model No. : 403SH
FCC ID : APYHRO00221
Test standard : FCC Part 15 Subpart B 2015 Class B
Test Result : Complied

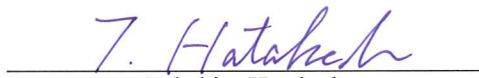
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4. The test results in this report are traceable to the national or international standards.
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6. This test report covers EMC technical requirements. It does not cover administrative issues such as Manual or non-EMC test related Requirements. (if applicable)

Date of test: May 7 and 8, 2015

**Representative
test engineer:**


Shinichi Miyazono
Engineer
Consumer Technology Division

Approved by :


Takahiro Hatakeda
Leader
Consumer Technology Division



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.
*As for the range of Accreditation in NVLAP, you may refer to the WEB address,
<http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap>

**UL Japan, Inc.
Ise EMC Lab.**

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13-EM-F0429

REVISION HISTORY

Original Test Report No.: 10775427H-B

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SECTION 1: Customer information

Company Name : Sharp Corporation, Communication Systems Division.
Address : 2-13-1 Iida Hachihonmatsu HigashiHiroshima-City, Hiroshima, 739-0192
Japan
Telephone Number : +81-82-420-1552
Facsimile Number : +81-82-420-1572
Contact Person : Hiroyuki Uwatoko

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Smart Phone
Model No. : 403SH
Serial No. : Refer to Section 4, Clause 4.2
Receipt Date of Sample : April 28, 2015
Country of Mass-production : China
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product description

Feature of EUT : 403SH is AXGP, Tri-band FDD-LTE(Band 1 / 3 / SBM Specific), Dual-band WCDMA (FDD I / VIII) & Tri-band GSM (900 / 1800 / 1900) Multi-mode Smart Phone.
The EUT has the function that NFC, Bluetooth and Wireless-LAN technology interface for establishing contact and transmitting data with certain device.
Clock frequencies in the system : CPU: 1.1904GHz (max)
Source oscillation: 19.2MHz, 27.12MHz (NFC/FeliCa), 27MHz (DTV)
RTC: 32.768kHz

SECTION 3: Test specification, procedures & results

3.1 Test specification

Test specification : FCC Part 15 Subpart B: 2015, final revised on January 21, 2015

Title : FCC 47CFR Part15 Radio Frequency Device
Subpart B Unintentional Radiators

3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	ANSI C63.4: 2009 7. AC powerline conducted emission measurements	Class B	N/A	[QP] 13.6 dB 0.17070 MHz, L [AV] 10.2 dB 0.17070 MHz, L	Complied
Radiated emission	ANSI C63.4: 2009 8. Radiated emission measurements	Class B	N/A	8.0 dB 60.320 MHz, Horizontal, QP	Complied

*Note: UL Japan, Inc's EMI Work Procedure 13-EM-W0420.

3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Conducted emission (+dB)
	150 kHz – 30 MHz
No.1	3.5 dB
No.2	3.5 dB
No.3	3.6 dB
No.4	3.5 dB

Test room (semi-anechoic chamber)	Radiated emission (10 m*)(+dB)		
	9 kHz - 30 MHz	30 MHz - 300 MHz	300 MHz - 1 GHz
No.1	4.0 dB	5.1 dB	4.7 dB
No.2	-	-	-
No.3	-	-	-
No.4	-	-	-

*10 m = Measurement distance

Test room (semi-anechoic chamber)	Radiated emission						
	(3 m*)(+dB)				(1 m*)(+dB)		(0.5 m*)(+dB)
	9 kHz - 30 MHz	30 MHz - 300 MHz	300 MHz - 1GHz	1 GHz - 10 GHz	10 GHz - 18 GHz	18 GHz - 26.5 GHz	26.5 GHz - 40 GHz
No.1	4.0 dB	5.1 dB	5.0 dB	5.1 dB	6.0 dB	4.9 dB	4.3 dB
No.2	3.9 dB	5.2 dB	5.0 dB	4.9 dB	5.9 dB	4.7 dB	4.2 dB
No.3	4.3 dB	5.1 dB	5.2 dB	5.2 dB	6.0 dB	4.8 dB	4.2 dB
No.4	4.6 dB	5.2 dB	5.0 dB	5.2 dB	6.0 dB	5.7 dB	4.2 dB

*3 m / 1 m / 0.5 m = Measurement distance

Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

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3.5 Test Location

UL Japan, Inc. Ise EMC Lab. *NVLAP Lab. code: 200572-0
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN
Telephone : +81 596 24 8999 Facsimile : +81 596 24 8124

	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	2973C-1	19.2 x 11.2 x 7.7 m	7.0 x 6.0 m	No.1 Power source room
No.2 semi-anechoic chamber	2973C-2	7.5 x 5.8 x 5.2 m	4.0 x 4.0 m	-
No.3 semi-anechoic chamber	2973C-3	12.0 x 8.5 x 5.9 m	6.8 x 5.75 m	No.3 Preparation room
No.3 shielded room	-	4.0 x 6.0 x 2.7 m	N/A	-
No.4 semi-anechoic chamber	2973C-4	12.0 x 8.5 x 5.9 m	6.8 x 5.75 m	No.4 Preparation room
No.4 shielded room	-	4.0 x 6.0 x 2.7 m	N/A	-
No.5 semi-anechoic chamber	-	6.0 x 6.0 x 3.9 m	6.0 x 6.0 m	-
No.6 shielded room	-	4.0 x 4.5 x 2.7 m	4.0 x 4.5 m	-
No.6 measurement room	-	4.75 x 5.4 x 3.0 m	4.75 x 4.15 m	-
No.7 shielded room	-	4.7 x 7.5 x 2.7 m	4.7 x 7.5 m	-
No.8 measurement room	-	3.1 x 5.0 x 2.7 m	N/A	-
No.9 measurement room	-	8.8 x 4.6 x 2.8 m	2.4 x 2.4 m	-
No.11 measurement room	-	6.2 x 4.7 x 3.0 m	4.8 x 4.6 m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0 m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test data, Test instruments, and Test set up

Refer to APPENDIX.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Smart Phone	403SH	004401/11/546637/3	Sharp Corporation	EUT
B	microSD Memory Card	SD-MD008GA	None	TOSHIBA	-
C	Personal Computer	PP11L	CN-0D4571-48643-55V-1651	Dell	-
D	Mouse	M-BE55	LZE21450232	Logitech	-
E	AC Adapter(PC)	PA-1650-05D2	CN-0F7970-71615-561-14A1	Dell	-
F	Printer	895Cxi	SG8BL1W16V	Hewlett Packard	-
G	AC Adapter(Printer)	C4557-60004	C8K28B	Hewlett Packard	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	USB Data Cable	0.80	Shielded	Shielded	-
2	Mouse Cable	0.72	Unshielded	Unshielded	-
3	AC Adaptor Cable (PC)	1.76	Unshielded	Unshielded	-
4	AC Power Cable (PC)	0.85	Unshielded	Unshielded	-
5	Parallel Cable	1.65	Shielded	Shielded	-
6	AC Adapter Cable (printer)	2.00	Unshielded	Unshielded	-
7	AC Power Cable (printer)	1.75	Unshielded	Unshielded	-

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SECTION 5: Conducted Emission

5.1 Operating environment

Test place	: No. 1 semi anechoic chamber
Temperature	: See data
Humidity	: See data

5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane.

The rear of tabletop was located 40 cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80 cm from any other grounded conducting surface. EUT was located 80 cm from the LISN/AMN and excess AC cable was bundled in center. I/O cables that were connected to the other peripherals were bundled in center. They were folded back and forth forming a bundle 30 cm to 40 cm long and were hung at a 40 cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/AMN to the input power source. All unused 50 ohm connectors of the LISN/AMN were resistivity terminated in 50 ohm when not connected to the measuring equipment. Photographs of the set up are shown in Appendix 3.

Frequency range	: 0.15 MHz - 30 MHz
EUT position	: Table top
EUT operation mode	: See Clause 4.1

5.3 Test procedure

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT within a semi anechoic chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains network (AMN). An overview sweep with peak detection has been performed. The measurements have been performed with a quasi-peak detector and if required, with an average detector.

The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type	: Quasi-Peak and CISPR AV
IF Bandwidth	: 9 kHz

5.4 Test result

Summary of the test results: Pass

Date: May 8, 2015

Test engineer: Shinichi Miyazono

UL Japan, Inc.

Ise EMC Lab.

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SECTION 6: Radiated Emission

6.1 Operating environment

Test place : No. 1 semi anechoic chamber
Temperature : See data
Humidity : See data

6.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane.

The EUT was set on the edge of the tabletop.

Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.

Photographs of the set up are shown in Appendix 3.

6.3 Test conditions

Frequency range : 30 MHz - 300 MHz (Biconical antenna) / 300 MHz - 1000 MHz (Logperiodic antenna)
1000 MHz - 6000 MHz (Horn antenna)
Test distance : 3 m
EUT position : Table top
EUT operation mode : See Clause 4.1

6.4 Test procedure

The height of the measuring antenna varied between 1 m and 4 m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver

The radiated emission measurements were made with the following detector function of the Test Receiver

Frequency	Below 1 GHz	Above 1 GHz
Instrument used	Test Receiver	Test Receiver
IF Bandwidth	QP: BW 120 kHz	PK: BW 1 MHz, CISPR AV: BW 1 MHz

- The noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

6.5 Test result

Summary of the test results: Pass

Date: May 7 and 8, 2015 Test engineer: Shinichi Miyazono

UL Japan, Inc.

Ise EMC Lab.

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Radiated Emission
(Below 1GHz)

DATA OF RADIATED EMISSION TEST

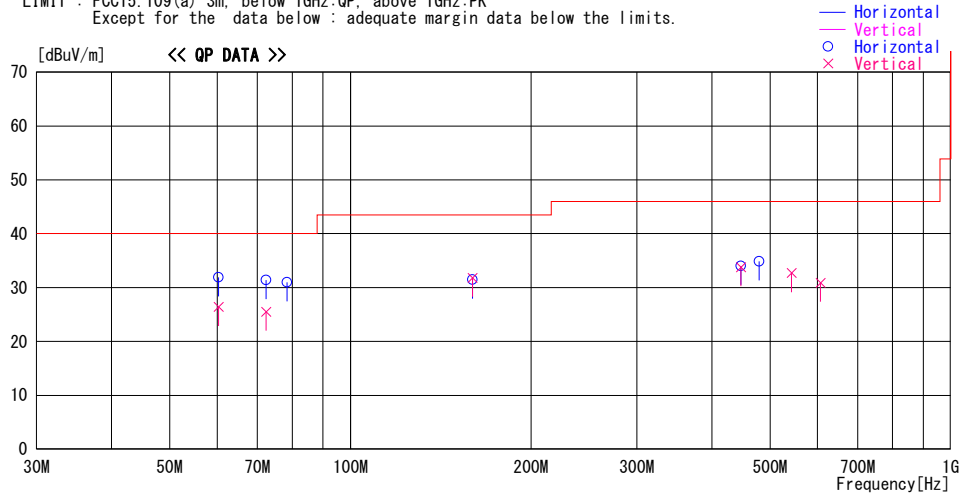
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2015/05/07

Report No. : 10775427H

Temp./Humi. : 22deg. C / 55% RH
Engineer : Shinichi Miyazono

Mode / Remarks : USB Data Com Mode Worst-Axis (Hori: X / Vert: X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency	Reading	DET	Antenna		Level	Angle	Height	Polar.	Limit	Margin	Comment
			Factor	Loss& Gain							
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]	
60.314	50.1	QP	7.3	-31.0	26.4	8	267	Vert.	40.0	13.6	
60.315	55.6	QP	7.3	-31.0	31.9	274	351	Hori.	40.0	8.1	
72.377	50.0	QP	6.3	-30.8	25.5	252	100	Vert.	40.0	14.5	
72.381	55.9	QP	6.3	-30.8	31.4	305	257	Hori.	40.0	8.6	
78.414	55.0	QP	6.7	-30.7	31.0	303	235	Hori.	40.0	9.0	
159.769	46.1	QP	15.4	-29.7	31.8	162	100	Vert.	43.5	11.7	
159.771	45.8	QP	15.4	-29.7	31.5	307	204	Hori.	43.5	12.0	
447.354	42.9	QP	17.8	-26.9	33.8	31	135	Vert.	46.0	12.2	
447.356	43.1	QP	17.8	-26.9	34.0	130	170	Hori.	46.0	12.0	
479.310	43.5	QP	17.9	-26.5	34.9	122	130	Hori.	46.0	11.1	
543.217	39.9	QP	18.7	-25.9	32.7	323	112	Vert.	46.0	13.3	
607.123	37.0	QP	19.5	-25.6	30.9	334	100	Vert.	46.0	15.1	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE + ATTEN. - GAIN(AMP))

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Below 1GHz)

DATA OF RADIATED EMISSION TEST

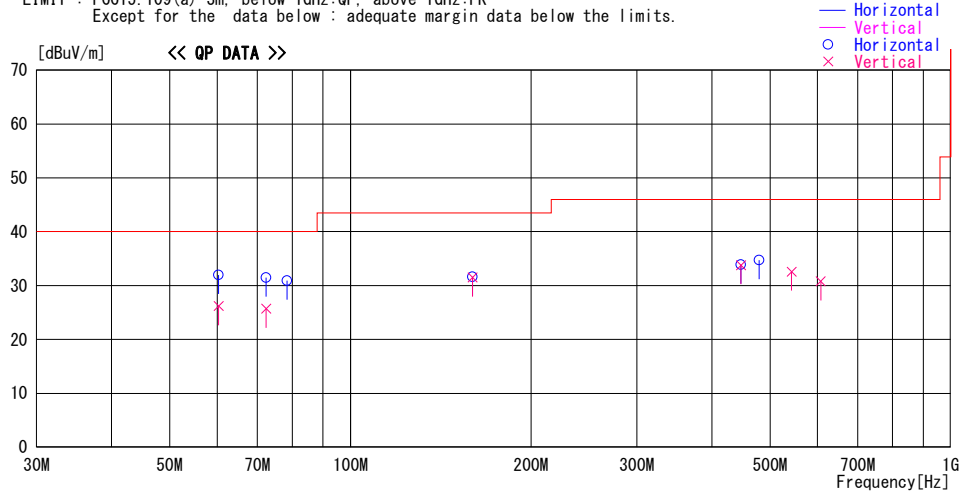
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2015/05/07

Report No. : 10775427H

Temp./Humi. : 22deg. C / 55% RH
Engineer : Shinichi Miyazono

Mode / Remarks : Standby Mode Worst-Axis (Hori: X / Vert: X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
60.320	55.7	QP	7.3	-31.0	32.0	259	346	Hori.	40.0	8.0	
60.324	49.9	QP	7.3	-31.0	26.2	6	285	Vert.	40.0	13.8	
72.384	56.0	QP	6.3	-30.8	31.5	298	247	Hori.	40.0	8.5	
72.387	50.2	QP	6.3	-30.8	25.7	249	100	Vert.	40.0	14.3	
78.414	54.9	QP	6.7	-30.7	30.9	304	233	Hori.	40.0	9.1	
159.769	45.8	QP	15.4	-29.7	31.5	170	100	Vert.	43.5	12.0	
159.770	45.9	QP	15.4	-29.7	31.6	304	197	Hori.	43.5	11.9	
447.354	42.9	QP	17.8	-26.9	33.8	28	131	Vert.	46.0	12.2	
447.357	43.0	QP	17.8	-26.9	33.9	131	160	Hori.	46.0	12.1	
479.314	43.3	QP	17.9	-26.5	34.7	112	157	Hori.	46.0	11.3	
543.216	39.8	QP	18.7	-25.9	32.6	322	112	Vert.	46.0	13.4	
607.216	36.9	QP	19.5	-25.6	30.8	332	100	Vert.	46.0	15.2	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE + ATTEN. - GAIN(AMP))

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Radiated Emission (Above 1GHz)

DATA OF RADIATED EMISSION TEST

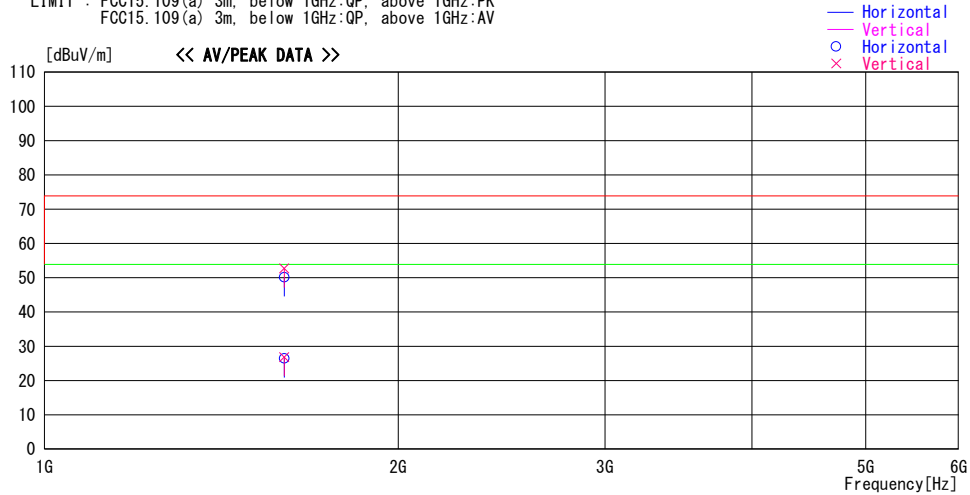
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2015/05/08

Report No. : 10775427H

Temp./Humi. : 22deg. C / 52% RH
Engineer : Shinichi Miyazono

Mode / Remarks : USB Data Com Mode Worst-Axis (Hori: X / Vert: X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
1599.992	59.0	PK	25.2	-34.1	50.1	279	216	Hori.	73.9	23.8	
1599.992	35.4	AV	25.2	-34.1	26.5	279	216	Hori.	53.9	27.4	
1600.000	35.8	AV	25.2	-34.1	26.9	243	120	Vert.	53.9	27.0	
1600.000	61.6	PK	25.2	-34.1	52.7	243	120	Vert.	73.9	21.2	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz:-HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE - GAIN(AMP))

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Radiated Emission (Above 1GHz)

DATA OF RADIATED EMISSION TEST

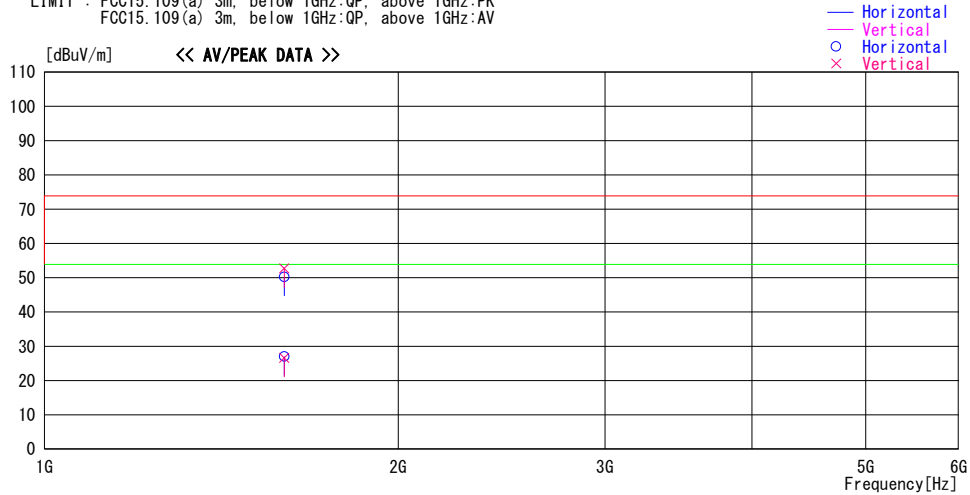
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Engineer : Shinichi Miyazono

Mode / Remarks : Standby Mode Worst-Axis (Hori: X / Vert: X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
1599.998	35.5	AV	25.2	-34.1	26.6	242	127	Vert.	53.9	27.3	
1599.998	61.6	PK	25.2	-34.1	52.7	242	127	Vert.	73.9	21.2	
1599.999	59.1	PK	25.2	-34.1	50.2	282	216	Hori.	73.9	23.7	
1599.999	35.9	AV	25.2	-34.1	27.0	282	216	Hori.	53.9	26.9	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE - GAIN(AMP))

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

APPENDIX 2: Test instruments

EMI Test Instruments

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-01	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 10m	DA-06881	RE/CE	2014/09/01 * 12
MOS-27	Thermo-Hygrometer	CUSTOM	CTH-201	A08Q26	RE/CE	2015/01/13 * 12
MJM-21	Measure	KOMELON	KMC-36	-	RE/CE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-
MTR-09	EMI Test Receiver	Rohde & Schwarz	ESU26	100412	RE/CE	2014/06/06 * 12
KBA-05	Biconical Antenna	Schwarzbeck	BBA9106	2513	RE	2014/11/22 * 12
KLA-04	Logperiodic Antenna	Schwarzbeck	USLP9143	361	RE	2014/11/22 * 12
MAT-08	Attenuator(6dB)	Weinschel Corp	2	BK7971	RE	2014/11/20 * 12
MCC-02	Coaxial Cable	Suhner/storm/Agilent/TSJ	-	-	RE	2014/09/12 * 12
MPA-19	Pre Amplifier	MITEQ	MLA-10K01-B01-35	1237616	RE	2015/02/03 * 12
MHA-05	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	253	RE	2014/05/16 * 12
MPA-01	Pre Amplifier	Agilent	8449B	3008A01671	RE	2015/02/04 * 12
MCC-165	Microwave Cable	Junkosha	MWX221	1203S213(1m) / 1311S166(5m)	RE	2014/11/11 * 12
MTW-01	Torque wrench	HUBER+SUHNER	74 Z-0-0-21	98019	RE	2015/01/16 * 36
MLS-25	LISN(AMN)	Schwarzbeck	NSLK8127	8127-731	CE(AE)	2014/07/09 * 12
MLS-26	LISN(AMN)	Schwarzbeck	NSLK8127	8127-732	CE(EUT)	2014/07/09 * 12
MTA-30	Terminator	TME	CT-01	-	CE	2015/01/19 * 12
MCC-03	Coaxial Cable	Fujikura/Suhner/TSJ	5D-2W(20m)/ 3D-2W(7.5m)/ RG400u(1.5m)/ RFM-E421(Switcher)	-/01068 (Switcher)	CE	2014/09/12 * 12
MAT-64	Attenuator(13dB)	JFW Industries, Inc.	50FP-013H2 N	-	CE	2015/01/29 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

CE: Conducted Emissions

RE: Radiated Emissions

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Ise EMC Lab.

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